

INTRODUCTION

KEMET solid tantalum capacitors are identified by the initial "T," followed by a unique "Series" number; for example, T110, T322, T350, etc. Each Series denotes a general physical form and type of encapsulation, as well as limits on dimensions and certain electrical characteristics under standard conditions of 25°C, 50% relative humidity, and one atmosphere pressure. Specific requirements are set forth in the respective Product Series in this catalog. All Military products are 100% electrically screened for the parameters shown in the respective product section. For non-military product, all series are 100% screened for leakage, capacitance and dissipation factor. All Series are inspected to electrical limits using a minimum .1% AQL sampling plans, according to the Military Standard MIL-STD-105, even after 100% testing. This sampling plan, to the best of KEMET Electronics' knowledge, meets or exceeds the generally accepted industry standard for similar products. KEMET capacitors may also be supplied, with prior agreement, to meet specifications with requirements differing from those of KEMET catalogs. **Reference ESR values are provided but are NOT 100% screened**

These Notes apply generally to all KEMET solid tantalum capacitors and illustrate typical performance under normal application conditions, except where noted. Certain Series will respond differently to various environmental conditions. For example, hermetically sealed series are relatively immune to humidity effects, while plastic-encased series are not. The intent of these Notes is not to delineate such differences but to provide general information concerning performance characteristics.

1. GENERAL APPLICATION CLASS

Solid tantalum capacitors are usually applied in circuits where the AC component is small compared to the DC component. Typical uses known to KEMET Electronics include blocking, by-passing, decoupling, and filtering. They are also used in timing circuits. If two of these polar capacitors are connected "back-to-back" (i.e., negative-to-negative or positive-to-positive), the pair may be used in AC applications (as a non-polar device).

2. STORAGE CONDITIONS

Capacitors may be stored without applied voltage over the operating temperature range specified in the catalogs for each Series. The range is from -55 to +125° C for all Series.

Tantalum capacitors do not lose capacitance from the "de-forming" effect as do liquid-electrolytic capacitors. Storage at high temperature may cause a small, temporary increase in leakage current (measured under standard conditions), but the original value is usually restored within a few minutes after application of rated voltage.

Series which are not hermetically sealed exhibit reversible changes in parameters with respect to relative humidity (RH). Capacitance increases with increasing humidity. The limiting change, reached upon establishment of equilibrium with the environment, is approximately -5% to +12% over the range from 25% to 95% RH, referred to the standard 50% RH. The amount of change is dependent upon size (capacitance and voltage rating, ie: CV product); small sizes might change no more than ±5%. Equilibrium at such extremes is seldom attained by plastic-cased capacitors, and the change in capacitance is consequently less. The rate of response to humidity changes increases with increasing temperature. Dissipation factor also increases with increasing RH. The

limiting change, at equilibrium with 95% RH, is approximately 50%.

DC leakage current may rise upon exposure to a combination of high temperature and high humidity, but is normally restored by voltage conditioning under standard conditions. The increase will be greater than that experienced under temperature influence alone because of conduction through absorbed water.

Hermetically-sealed and non-hermetic Series may be affected by absorption of water on external insulating surfaces. The water film may also attract a layer of dust from the air, increasing the effect. The most sensitive parameter is leakage current.

3. POLARITY

These capacitors are inherently polar devices and may be permanently damaged or destroyed if connected with the wrong polarity. The positive terminal is identified on the capacitor body by a polarity mark and the capacitor body may include an obvious geometrical shape. However, some Series contain two capacitors connected (negative-to-negative) to form "non-polar" capacitors. Rated voltage (see para. 8) may be applied to these Series in either direction.

4. OPERATING ENVIRONMENT

Most of the discussion under "Storage Conditions" will apply also when capacitors are operated within the applicable electrical ratings described below. The temporary increase in leakage current (at standard conditions) following elevated-temperature exposure is not observed, however, if the capacitors are operated with adequate DC voltage applied.

5. CAPACITANCE

Capacitance is measured at 120 Hz and 25° C with up to 1 volt rms applied. Note that, in either operation, peak AC plus DC bias must not exceed either rated voltage (normally polarized) or 15% of rated voltage in the reverse direction at 25°C. Measurement circuits are of high impedance, however, and under these conditions 1 volt rms may be applied even to 6 volt capacitors (23% peak reversal) without a DC bias. DC bias is thus normally not used, except when rated voltage is below 6 volts and the AC signal level exceeds 0.3 vrms. However, MIL-C-39003 provides for up to 2.2 volts DC. DC bias is not commonly used at room temperature, but is more commonly used at elevated temperatures.

DC bias causes a small reduction in capacitance, up to about 2% when full rated voltage is applied as bias. DF is also reduced by the presence of DC; rated voltage may cause a decrease in DF of about 0.2% (e.g., a decrease from 3.6 to 3.4% DF).

Capacitance changes very little below 1 kHz but decreases more noticeably at higher frequencies. Larger capacitance values decline more rapidly than small ratings. The effect of frequency upon capacitance is shown in Figure 1.

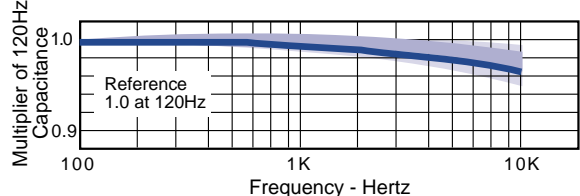


Figure 1. Normal Effect of Frequency upon Capacitance

Capacitance typically changes with temperature according to the curve of Figure 2.

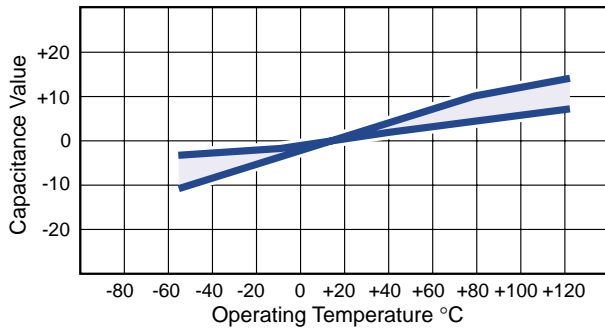


Figure 2. Typical Effect of Temperature upon Capacitance

6. DISSIPATION FACTOR (DF)

DF is measured at 120 Hz and 25° C with up to 1 volt rms applied. Note that, in either operation, peak AC plus DC bias must not exceed either rated voltage (normally polarized) or 15% of rated voltage in the reverse direction at 25°C. Measurement circuits are of high impedance, however, and under these conditions 1 volt rms may be applied even to 6 volt capacitors (23% peak reversal) without a DC bias. DC bias is thus normally not used, except when rated voltage is below 6 volts and the AC signal level exceeds 0.3 vrms. However, MIL-C-39003 provides for up to 2.2 volts DC. DC bias is not commonly used at room temperature, but is more commonly used at elevated temperatures.

Dissipation Factor (DF) is a useful low-frequency measure of the resistive component in capacitors. It is the ratio of the unavoidable resistance to the capacitive reactance, usually expressed in percent. DF increases with temperature above +25° C and may also increase at lower temperatures. Unfortunately, one general limit for DF cannot be specified for all capacitance/voltage combinations, nor can response to temperature be simply stated. Catalogs for the respective series list DF limits under various conditions.

Dissipation factor increases with increasing frequency as would be expected from the decreasing capacitive reactance. DF is not a very useful parameter above about 1 kHz. The DF of larger capacitance values increases more rapidly than that of smaller ratings. Figure 3 shows typical effect of frequency on DF.

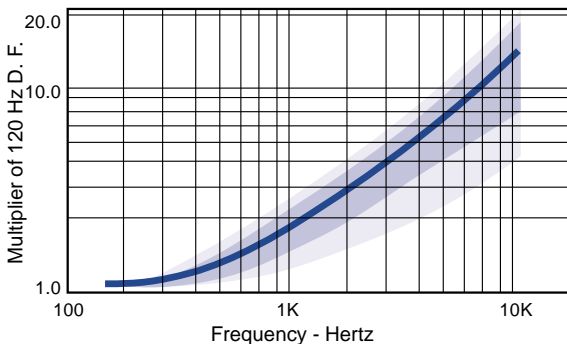


Figure 3. Normal Effect of Frequency upon Dissipation Factor

DC bias causes a small reduction in capacitance, up to about 2% when full rated voltage is applied, as bias. DF is also reduced by the presence of DC bias. Rated voltage may cause a decrease in DF of about 0.2% (e.g., a decrease from 3.6 to 3.4% DF).

DF is defined as $\frac{ESR}{X_c}$ and is also referred to occasionally, as $\tan d$ or “loss tangent.” The “Quality Factor,” Q , is the reciprocal of DF (DF is not expressed in

percent in this calculation). Another expression, rarely used, is the “power factor,” or $\frac{ESR}{Z}$. Power factor is $\cos u$, while DF is $\tan u$.

7. DC LEAKAGE (DCL)

DC leakage is affected by voltage to a much larger extent, and this effect can frequently be used to advantage in circuits where only very low leakage currents can be tolerated. Typical response of DCL to applied voltage is illustrated in Figure 4.

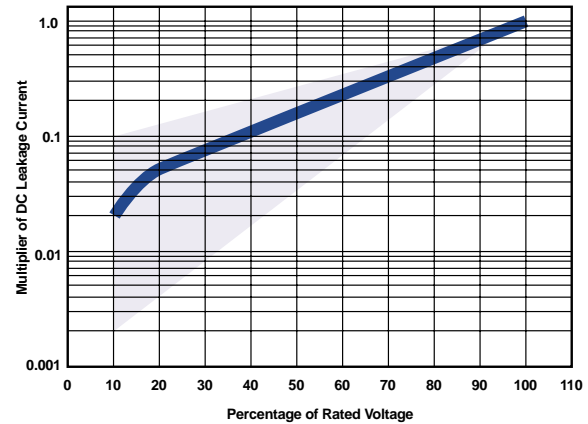


Figure 4. Typical Range of DC Leakage as a Function of Applied Voltage

DC leakage current (DCL) increases with increasing temperature according to the typical curve of Figure 5.

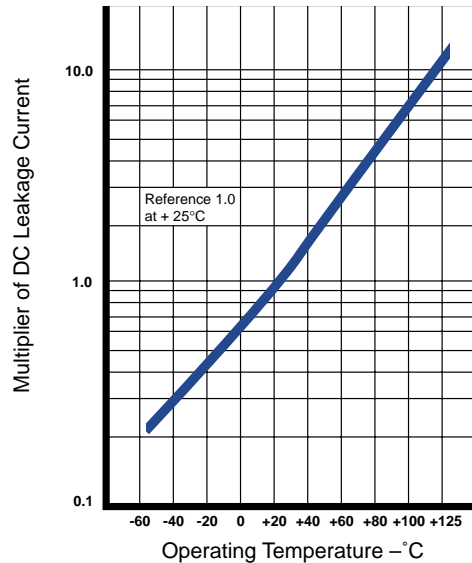


Figure 5. Typical Effect of Temperature upon DC Leakage Current

Leakage current is measured at a rated voltage through +85°C and may also be measured at +125°C with 2/3 of rated voltage applied.

8. RATED VOLTAGE

This term refers to the maximum continuous DC working voltage permissible at temperatures of +85° C or below. The lower operating temperature is specified as -55° C. Operation above +85° C is permissible, with reduced working voltage. Typical working voltage reduction is to 2/3 of rated voltage at +125° C.

9. WORKING VOLTAGE

This is the maximum recommended peak DC operating voltage for continuous duty at or below 85°C without DC voltage surges or AC ripple superimposed. No voltage derating is required below 85°C. Capacitors may be operated to 125°C with working voltage linearly derated to 2/3 of the 85°C rating at 125°C as shown in Figure 6.

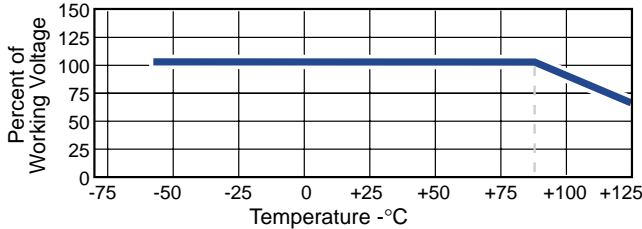


Figure 6. Working Voltage Change with Temperature

10. SURGE VOLTAGE

Surge voltage is defined as the maximum voltage to which the capacitor should be subjected under transient conditions, including peak AC ripple and all DC transients.

DC Working Voltage @ 85°C	2	3	4	6	10	15/16	20	25	35	50	60	75	100	125
Surge Voltage @ 85°C	2.6	4	5.3	8	13	20	26	33	46	65	78	98	130	140

TABLE 1 Surge Voltage Ratings

A typical surge voltage test is performed at +85°C with the applicable surge voltage per Table 1. The surge voltage is applied for 1000 cycles of 30 seconds on voltage through a 33 ohm series resistor and 30 seconds off voltage with the capacitor discharged through a 33 ohm resistor. Upon completing the test, the capacitors are allowed to stabilize at room temperature. Capacitance, DF, and DCL are then tested:

1. The DCL should not exceed the initial 25°C limit.
2. The capacitance should be within ±10% of initial value.
3. The DF should not exceed the initial 25°C limit.

11. REVERSE VOLTAGE

Although these are polar capacitors, some degree of transient voltage reversal is permissible, as seen below. The capacitors should not be operated continuously in reverse mode, even within these limits.

Temperature, °C.	Percentage of Rated Voltage
+25	15
+85	5
+125	1

TABLE 2 Reverse Voltage Ratings

12. EQUIVALENT SERIES RESISTANCE (ESR)

Equivalent Series Resistance (ESR) is the preferred high-frequency statement of the resistance unavoidably appearing in these capacitors. ESR is not a pure resistance, and it decreases with increasing frequency. Typical ESR limits are established in each specific product series. However, the ESR limits provided are for reference only, and are not necessarily the actual value that a particular Series product will attain.

Total impedance of the capacitor is the vector sum of capacitive reactance (X_C) and ESR, below resonance; above resonance total impedance is the vector sum of inductive reactance (X_L) and ESR.

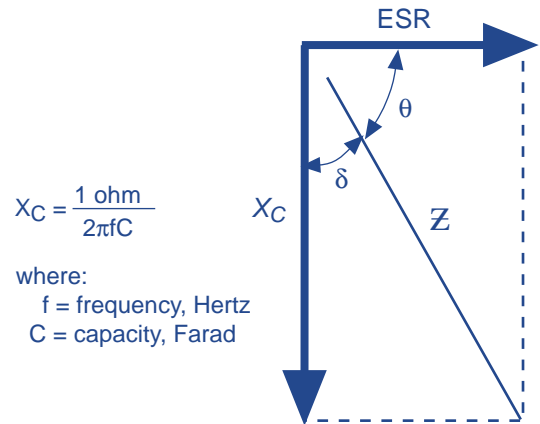


Figure 7a Total Impedance of the Capacitor Below Resonance

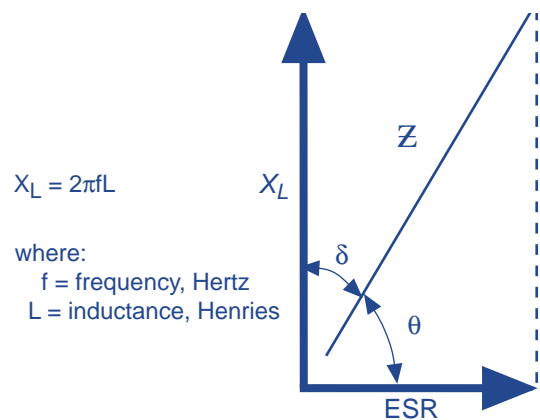


Figure 7b Total Impedance of the Capacitor Above Resonance

To understand the many elements of a capacitor, see Figure 8.

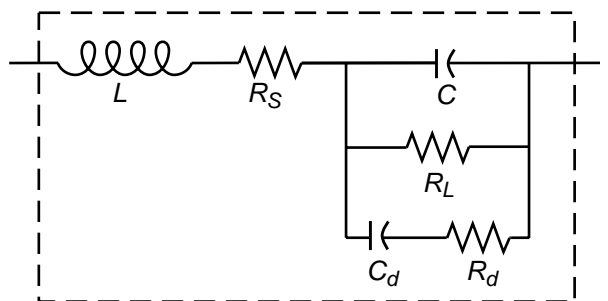


Figure 8. The Real Capacitor

A capacitor is a complex impedance consisting of many series and parallel elements, each adding to the complexity of the measurement system.

L — Represents lead wire and construction inductance. In most instances (especially in solid tantalum and

monolithic ceramic capacitors) it is insignificant at the basic measurement frequencies of 120 and 1000 Hz.

RS — Represents the actual ohmic series resistance in series with the capacitance. Lead wires and capacitor electrodes are contributing sources.

RL — Capacitor Leakage Resistance. Typically it can reach 50,000 megohms in a tantalum capacitor. It can exceed 10^{12} ohms in monolithic ceramics and in film capacitors.

Rd — The dielectric loss contributed by dielectric absorption and molecular polarization. It becomes very significant in high frequency measurements and applications. Its value varies with frequency.

Cd — The inherent dielectric absorption of the solid tantalum capacitor which typically equates to 1-2% of the applied voltage.

As frequency increases, X_C continues to decrease according to its equation above. There is unavoidable inductance as well as resistance in all capacitors, and at some point in frequency, the reactance ceases to be capacitive and becomes inductive. This frequency is called the self-resonant point. In solid tantalum capacitors, the resonance is damped by the ESR, and a smooth, rather than abrupt, transition from capacitive to inductive reactance ($X_L = 2\pi fL$) follows.

35VDC Rated

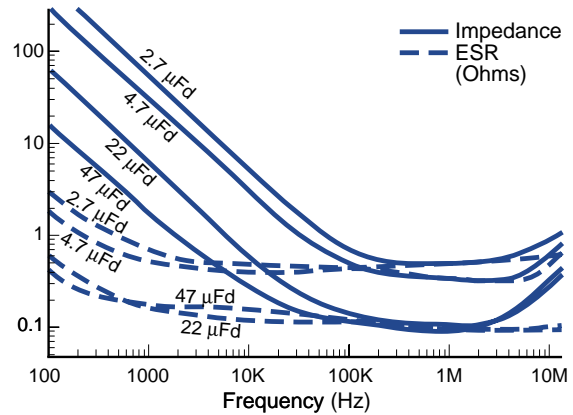


Figure 11a. ESR and Impedance vs. Frequency

Typical ESR and Z performance is given for representative capacitor ratings in Figures 9 through 11. Measured impedance will be affected by the length of lead wire included. Data for the curves were taken by including 1/2" of each lead wire in the measuring circuit.

Despite the fact that the reactance is entirely inductive above the self-resonance, these capacitors find use as decoupling devices above 10 MHz. Special designs have been developed for minimum inductance and are used above 100 MHz.

ESR and Z are also affected by temperature. At 100 kHz, ESR decreases with increasing temperature. The amount of change is influenced by the size of the capacitor and is generally more pronounced on smaller ratings.

10VDC Rated

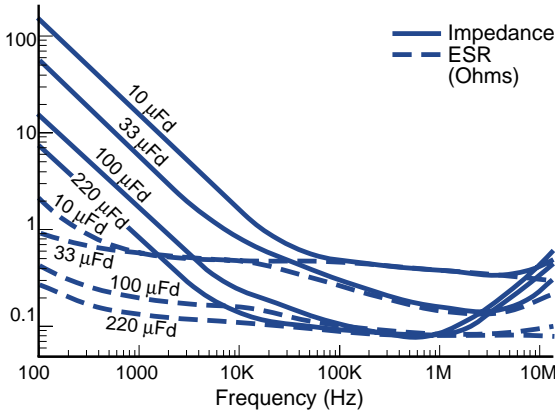


Figure 9. ESR and Impedance vs. Frequency

Multiplier of 100kHz ESR

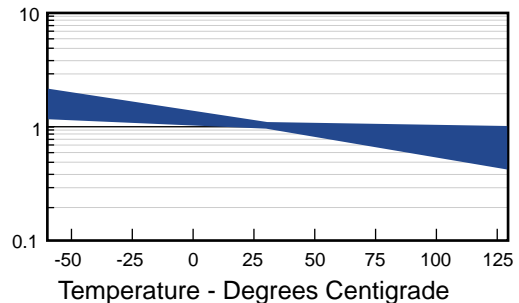


Figure 11b Typical Effect of Temperature on 100 kHz ESR

20VDC Rated

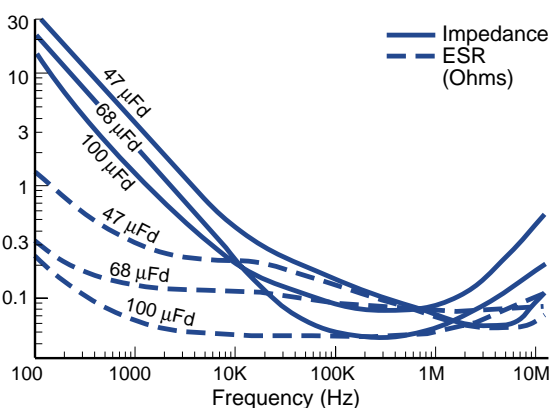


Figure 10. ESR and Impedance vs. Frequency

13. POWER DISSIPATION

Permissible power dissipation has been empirically established for all Series and is listed in each respective product section.

See pages 6-41 for herm seal, 42-50 for axial and radial molded, and 61-70 for tantalum dipped.

It is usually most convenient to translate the permissible power into an AC voltage rating. Assuming a sinusoidal waveform, the "ripple voltage" permissible may be calculated from the impedance and ESR data shown in the respective product section. However, three criteria must be observed:

1. Dissipated power must not exceed the limits specified for the Series.

2. The positive peak AC voltage plus the DC voltage must not exceed the maximum working voltage permitted at the ambient temperature.

3. The negative peak AC voltage, in combination with the DC voltage, must not exceed the permissible reverse voltage at the ambient temperature.

The rms ripple voltage limitation imposed by power dissipation is given by:

$$P = I^2R = \frac{E^2R}{Z^2}$$

where: I = rms ripple current (amperes)
 E = rms ripple voltage (volts)
 P = power (watts)
 Z = impedance at specified frequency (ohms)
 R = equivalent series resistance at specified frequency (ohms)

Maximum allowable rms ripple voltage may be determined as follows:

$$E(\text{max}) @ 25^\circ\text{C} = Z \sqrt{\frac{P(\text{max})}{R}}$$

$$E(\text{max}) = 85^\circ\text{C} = 0.9 E(\text{max}) @ 25^\circ\text{C}$$

$$E(\text{max}) @ 125^\circ\text{C} = 0.4 E(\text{max}) @ 25^\circ\text{C}$$

P(max) = maximum watts shown on Performance Characteristic pages 5, 42, 49, 58 and 61.

Permissible AC ripple current can be determined by the following:

$$I_{\text{rms}} = \sqrt{\frac{P(\text{max})}{R}}$$

If two polar capacitors are connected back-to-back, (1) the pair may be operated on AC without need for DC bias. The first two criteria above must be observed. If DC is applied, the sum of DC and peak AC must not exceed, in either direction, the maximum working voltage specified for the ambient temperature.

(1) Some KEMET Series provide convenient assemblies of non-polar pairs. The two negative terminals are connected internally. It is also permissible to connect the two positive terminals to form a non-polar pair.

14. LONG-TERM STABILITY

Within the general class of electrolytic capacitors, solid tantalum capacitors offer unusual stability of the three important parameters: capacitance, dissipation factor, and leakage current. These solid-state devices are not subject to the effects of electrolysis, deforming or drying-out associated with liquid-electrolyte capacitors.

When stabilized for measurement at standard conditions, capacitance will typically change less than $\pm 3\%$ during a 10,000 hour life test $+85^\circ\text{C}$. The same comparative change has been observed in shelf tests at $+25^\circ\text{C}$ extending for 50,000 hours. (Some of this change may stem from instrument or fixture error.)

Dissipation factor exhibits no typical trend. Data from 10,000 hour life tests at $+85^\circ\text{C}$ show that initial limits (at standard conditions) are not exceeded at the conclusion of these tests.

Leakage current is more variable than capacitance or DF; in fact, leakage current typically exhibits a logarithmic dependence in several respects. MIL-C-39003/1 permits leakage current (measured at standard conditions) to rise

by a factor of four over 10,000 hour life tests. Typical behavior shows a lower rate of change, which may be negative or positive. Initial leakage currents are frequently so low (less than 0.1 nanoampere in the smallest CV capacitors, to about 10 microampere in the largest CV types) that changes of several orders of magnitude have no discernable effect on the usual circuit designs.

15. FAILURE MODE

Capacitor failure may be induced by exceeding the rated conditions of forward DC voltage, reverse DC voltage, surge voltage, surge current, power dissipation, or temperature. As with any practical device, these capacitors also possess an inherent, although low, failure rate when operated within the rated condition.

The dominant failure mode is by short-circuit. Minor parametric drifts (see Section 14 "Long-Term Stability") are of no consequence in circuits suitable for solid tantalum capacitors. Catastrophic failure occurs as an avalanche in DC leakage current over a short (millisecond) time span. The failed capacitor, while called "short-circuited", may exhibit a DC resistance of 10 to 104 ohm.

If a failed capacitor is in an unprotected low-impedance circuit, continued flow of current through the capacitor may obviously produce severe overheating. This heat may melt the internal solder (all Series) and the sealing solder used in hermetic Series. The short-circuit failure may thereby be converted to an open-circuit failure. If the circuit does not open promptly, the over-heated capacitor may damage the circuit board or nearby components. Protection against such occurrence is obtained by current-limiting devices or fuses provided by the circuit design.

Fortunately, the inherent failure rate of KEMET solid tantalum capacitors is low, and this failure rate may be further improved by circuit design. Statistical failure rates are provided for those capacitors with characters other than "A" in the next-to-last position of the part number. Relating circuit conditions to failure rate is aided by the guides in the section following.

16. RELIABILITY PREDICTION

Three important application conditions largely control failure rate: DC voltage, temperature, and circuit impedance. Estimates of the respective effects are provided by the nomograph in Figure 12 and Table 3 following. The nomograph related failure rate to voltage and temperature while the table relates failure rate to impedance. These estimates apply to steady-state DC conditions, and they assume usage within all other rated conditions.

Standard conditions, which produce a unity failure rate factor, are rated voltage, $+85^\circ\text{C}$, and 0.1 ohm-per-volt circuit impedance. While voltage and temperature are straightforward there is sometimes difficulty in determining impedance. What is required is the circuit impedance seen by the capacitor. If several capacitors are connected in parallel, the impedance seen by each is lowered by the source of energy stored in the other capacitors. Energy is similarly stored in series inductors.

Failure rate is conventionally expressed in units of percent per thousand hours. As a sample calculation, suppose a particular batch of capacitors has a failure rate of 0.5% Khr under standard conditions. What would be predicted failure rate at 0.7 times rated voltage, $+60^\circ\text{C}$ and $0.8\Omega/\text{V}$? The nomograph gives a factor of 7×10^{-4} , and the table gives a factor of 0.3. The failure rate estimate is then:

$$0.5 \times 7 \times 10^{-4} \times 0.3 = 1.05 \times 10^{-4}, \text{ or } 0.0001\% \text{ Khr}$$

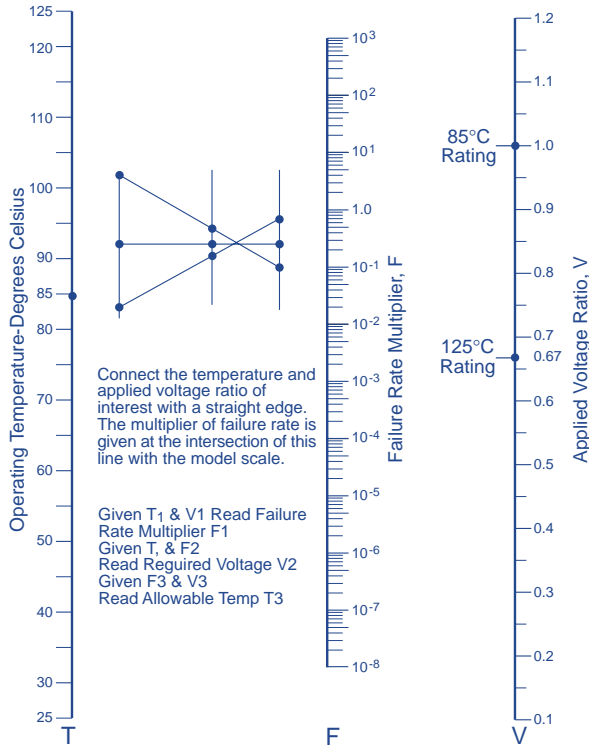


Figure 12. Reliability Nomograph

Circuit Impedance (ohms/volt)	Failure Rate Improvement (multiplying factors)
0.1	1.0
0.2	.8
0.4	.6
0.6	.4
0.8	.3
1.0	.2
2.0	.1
3 or greater	.07

TABLE 3 Relationship of Failure Rate to Impedance

Voltage “de-rating” is a common and useful approach to improved reliability. It can be pursued too far, however, when it leads to installation of higher voltage capacitors of much larger size. Inherent failure rate is roughly proportional to $CV^{1.6}$, where C is capacitance and V is rated voltage. The effect becomes particularly noticeable above 50-volt ratings. It is possible to lose more via higher inherent failure rate than is gained by voltage derating.

The relationships shown are more useful when the failure rate has been statistically determined for a given group of capacitors.

Failure rate is statistically determined for each production batch of KEMET High Reliability capacitors, as described in Specification GR500 Catalog F2956. As noted above, not all capacitance/voltage rate values are inherently equal in failure rate. GR500 capacitors are processed and subjected to 100% reliability testing as a homogeneous group of one capacitance/voltage value. Failure rate under standard conditions is available from 1 to 0.001% Khr, depending upon the capacitance/voltage value.

Several Series are qualified under U.S. military specification MIL-C-39003. Failure rates as low as 0.001%/Khr are available for all capacitance/voltage values in given groups under this test program. The specifications and

their accompanying Qualified Products Lists should be consulted for details.

For Series not covered by military specifications, and internal sampling program is operated by KEMET Quality Assurance. The confidence level chosen for reporting the data is 60%. However, the cost of sampling each batch produced is overwhelmingly prohibitive, and no claim is made concerning knowledge of failure rate for any particular lot shipped. It is demonstrated that average failure rate for all commercial Series is between .1 and 1%/Khr at standard conditions and 60% confidence after 2,000 hours' testing, +85°C, and rated voltage and ≤ 1 ohm total series resistance.

17. SURGE CURRENT

All conventional reliability testing is conducted under steady-state DC voltage. Experience indicates that AC ripple, within the limits prescribed, has little effect on failure rate. Heavy surge currents are possible in some applications, however. Circuit impedance may be very low (below the standard 0.1 ohm/volt) or there may be driving inductance to cause voltage “ringing.” Surge current may appear during turn-on of equipment, for example.

Failure rate under current-surge conditions may not be predictable from conventional life test data. A surge current test is utilized to ensure against a high frequency of such failures, and a description is available free of charge. The test has been adopted for all capacitors under MIL-C-39003/06/09/10 and KEMET's GR500 specifications.

18. ENVIRONMENTAL CONSIDERATION

It is not possible to foresee all the conditions to which capacitors may be subjected. Following is a list of standard tests which every Series will survive. Data may be available (upon request) under more severe stresses for certain Series.

- LIFE TEST 85°C OR 125°C, 2000 Hours: When subjected to 2000 hours at 85°C at full rated DC voltage, or 125°C at 2/3 of 85°C voltage, the capacitor shall meet the following requirements when tested at 25°C:

The DCL shall be within 1.25 times the initial DCL limit.

Capacitance shall be within $\pm 10\%$ of the initial measured value.

The DF shall not exceed the initial limit.

- SHELF LIFE +85°, 2000 hours. Post test of capacitor shall meet the following requirements when tested at 25°C:

The DCL shall be within 1.5 times the initial DCL limit.

Capacitance shall be within $\pm 10\%$ of the initial measured value.

The DF shall not exceed 1.5 times the initial limit.

- LEAD STRENGTH MIL-STD-202 Method 211: Pull test will be performed as in MIL-STD-202, Method 211. The following details and exceptions shall apply.
 - a. Test condition letter—A
 - b. The body of the capacitor will be securely clamped during test.

- c. Applied force—3 pounds (1.4 kg).
 - d. Test Condition letter—C (M39003 Test Condition letter—D)
 - e. Applied Force—1 pound, 3 bends.
- VIBRATION; HIGH FREQUENCY: Per MIL-STD-202, Method 204, Condition D, 10 Hz to 2000 Hz.
 - a. Mounting—Capacitors shall be mounted on a fixture by the body. Leads shall be supported by rigidly supported terminals.
 - b. Electrical load conditions—During the test, the specified DC rated voltage shall be applied to the capacitors.
 - c. Test condition letter—D (20 G).
 - d. Duration and direction of motion—4 hours in each of two mutually perpendicular directions (total of 8 hours), one parallel and the other perpendicular to the axis.
 - e. Measurements during vibration—During the last cycle, an electrical measurement shall be made to determine intermittent operation or open- or short-circuiting. Observations shall also be made to determine intermittent contact or arcing or open- or short-circuiting. Detecting equipment shall be sufficiently sensitive to detect any interruption with a duration of 0.5 ms, or greater.
 - f. Examination after test—Capacitors shall be visually examined for evidence of mechanical damage.
 - SHOCK TEST: Per MIL-STD-202, Method 213. The following details shall apply:
 - a. Special mounting means—Capacitors shall be rigidly mounted on a mounting fixture by the body. When securing leads, care shall be taken to avoid pinching the heads.
 - b. Test-condition letter—I (100 G peak). 6 ms. (saw-tooth)
 - c. Measurements and electrical loading during shock—During the test, observations shall be made to determine intermittent contact or arcing or open- or short-circuiting. Detecting equipment shall be sufficiently sensitive to detect any interruption with a duration of 0.5 ms. The DC rated voltage shall be applied to the capacitors during the test.
 - d. Examinations after test—Capacitors shall be visually examined for evidence of arcing, breakdown, and mechanical damage.
 - HUMIDITY LIFE TEST: Capacitors shall be capable of withstanding 1000 hours at 55°C with an ambient humidity of 90-95% RH with rated DC voltage applied. After the capacitors have stabilized for a period of 24 hours at 25°C, they shall meet the following limits:
 - DCL shall not exceed 5 times the initial limit.
 - Capacitance shall be within $\pm 10\%$ of the initial value.
 - DF shall not exceed 2 times the initial limit.
 - THERMAL SHOCK—MIL-STD-202, Method 107: Capacitors shall be subjected to thermal shock in accordance with MIL-STD-202, Method 107, Test Condition A. M39003 Components tested to MIL-STD-202, Method 107, Condition B. Measurements before and after cycling are required. Conditioning prior to the first cycle will be 15 minutes at the following standard inspection conditions:
 - a. Relative Humidity—Less than 50%.
 - b. Ambient Temperature—25°C $\pm 5^\circ\text{C}$.
 - c. Final measurements are made after stabilization at room temperature.
 - MOISTURE RESISTANCE—MIL-STD-202, Method 106: Capacitors shall be tested in accordance with MIL-STD-202, Method 106 including the following details:
 - a. Mounting—The capacitors shall be mounted by normal mounting means
 - b. Initial Measurements
 - c. Polarizing and Load Voltage—Not applicable
 - d. Final measurements—After the final cycle and within 2 to 6 hours after removal of the capacitors from the humidity chamber, capacitance, dissipation factor, and DC leakage will be measured.

DCL should not exceed the initial 25°C limit.
Capacitance should be within $\pm 10\%$ of the initial measured value.
DF should not exceed the initial 25°C limit.
 - RESISTANCE TO SOLVENTS — MIL-STD-202, Method 215:
 - Brushing required after test.
 - DCL meets limit shown in respective Part Number Tables.
 - Capacitance meets applicable tolerance.
 - DF meets limits shown in respective Part Number Tables.
 - No visible damage to case or marking.
 - RESISTANCE TO SOLDERING HEAT — MIL-STD-202, Method 210, Test Condition.
 - Letter B. (260° for 10 Sec.)
 - Leads shall be immersed to within $\frac{1}{4}$ inch of the capacitor body. Capacitance, DF, and DCL should meet original limits shown in respective Part Number Tables.
 - SOLDERABILITY — MIL-STD-202, Method 208;
 - Number of terminations on each capacitor tested: 2.
 - Depth of insertion in flux and solder to within .125" of capacitor body.
 - FLAMMABILITY — The encapsulant for Molded and Conformal Coated Product meets or exceeds the following requirements:
 - Underwriters Lab. UL 94V-0
 - Oxygen Index per ASTM-D-2863
 - 28% min.
 - STABILITY AT LOW AND HIGH TEMPERATURE
 - 55°C to 125°C: Capacitors will be capable of withstanding extreme temperature testing at a succession of continuous steps at +25°C, -55°C, +25°C, +85°C, +125°C, +25°C, in the order stated. Capacitors shall be brought to thermal stability at each test

temperature. Capacitance, DF, and DCL are measured at each test temperature except that DCL is not measured at -55°C. DC bias of 2.0 ±0.5 vdc is recommended for the capacitance and DF measurements.

When measurements are made at the various steps, the electrical limits for each temperature shall not exceed the following limits.

- Step 1, +25°C, DCL as indicated in original limit; capacitance within tolerance specified; DF as indicated in original limit shown in Part Number Tables.
- Step 2, -55°C, Capacitance within ±10% of initial value; ESR, DF within limit shown in Part Number Tables.
- Step 3, +25°C, DCL as indicated in original limit; capacitance within ±5% of initial value; ESR, DF within limit shown in Part Number Tables.
- Step 4, +85°C, DCL shall not exceed 10 times original DCL limit at 25°C. Capacitance shall be within ±10% of the initial value. DF shall be within 125% of limits shown in Part Number Tables. ESR shall be within limits shown in Part Number Tables.
- Step 5, +125°C, DCL shall not exceed 12.5 times the original limit at 25°C. Capacitance shall be within ±12% of initial value. DF shall be within 150% of limits shown in Part Number Tables. ESR shall be within limits shown in Part Number Tables.
- Step 6, +25°C, DCL as indicated in original limit; capacitance within ±5% of initial value; ESR, DF as indicated in original limit shown in Part Number Tables.

Note: M39003 specifies Δ's and limits by individual slash sheet.

- DAMP HEAT, STEADY STATE: Meets requirements of IEC Publication 384-15, method IEC 68-2-3. Climatic category 55/125/56.

19. MOUNTING

All encapsulated Series fall into two general classes. The first is provided with leads extending from opposite ends of the body, generally along the principle axis of the body ("axial leads"). The second is provided with parallel leads extending from one side or face of the body ("radial leads"). With either type, mounting points are normally provided by the leads themselves.

Axial leads may be used for point-to-point wiring, but usually, the wires are bent at 90° from the capacitor axis for insertion through printed circuit (PC) boards. Axial capacitors supplied on reels for machine insertion will

withstand the mechanical stresses of bending and inserting by all popular machines known to KEMET at this time. Most KEMET axial Series may be supplied on reels to feed such machines. Radial leads are intended to plug directly into holes of PC boards. Auto-machines will insert compatible radial capacitor designs, and most KEMET capacitors may be supplied in appropriate reeled forms (ARIS).

With either axial or radial types, attention should be paid to treatment of the capacitors during mounting and afterward under service conditions. Difficulty during mounting usually arises from lead damage or from overheating. Hand soldering technique or, more often, wave-solder machines cause the overheating. The internal cathode connection on most Series is made between solder and a silver-pigmented paint. If too much heat is applied, this solder may remelt and degrade the silver-solder interface or cause a direct short-circuit.

KEMET's hermetically-sealed series has an internal space into which molten cathode solder may run, depriving the cathode connection and possibly flowing across the terminals to short-circuit the capacitor from the inside. It is also possible to remelt the solder which bonds the rim of the glass-metal seal, causing loss of hermeticity and possibly a short-circuit. Finally, solder at the exit point of the positive wire may be remelted with similar effect. This solder is a high-temperature alloy, however, and it is much less likely to be melted. (Re-dipping of lead wires is practiced by some users, introducing another hazard of remelting this solder).

Plastic-encased Series have only one site of solder, the internal cathode connection. The rate of heat transfer through the plastic is lower than through the metal can of hermetic Series, but conduction along the negative lead-wire to remelt this solder is very similar. There is little internal void within plastic cases, so remelted solder tends to remain in its original location and solidify when heat is removed. Short-circuiting is very unlikely, but reliability of the internal connection may be compromised by leaching of silver from the paint into the molten solder. The latter effect degrades the cathode connection in hermetic parts as well.

All encased capacitors will pass the Resistance to Soldering Heat Test of MIL-STD-202, Method 210, Condition B. This test dips each leadwire into molten solder at +260° C for 10 seconds while the capacitor body is held vertically above the solder. KEMET capacitors will pass this test when the depth of immersion brings the capacitor body (or closest external solder joint, if it is closer as in some hermetic Series) to a minimum distance of 0.100 inches from the solder surface. This demonstration of resistance to solder heat is in accordance with what is believed to be the industry standard. More severe treatment must be considered reflective of an improper soldering process.

Shown in Figure 13 is a recommended solder wave profile for both axial and radial leaded solid tantalum capacitors.

Optimum Solder Wave Profile

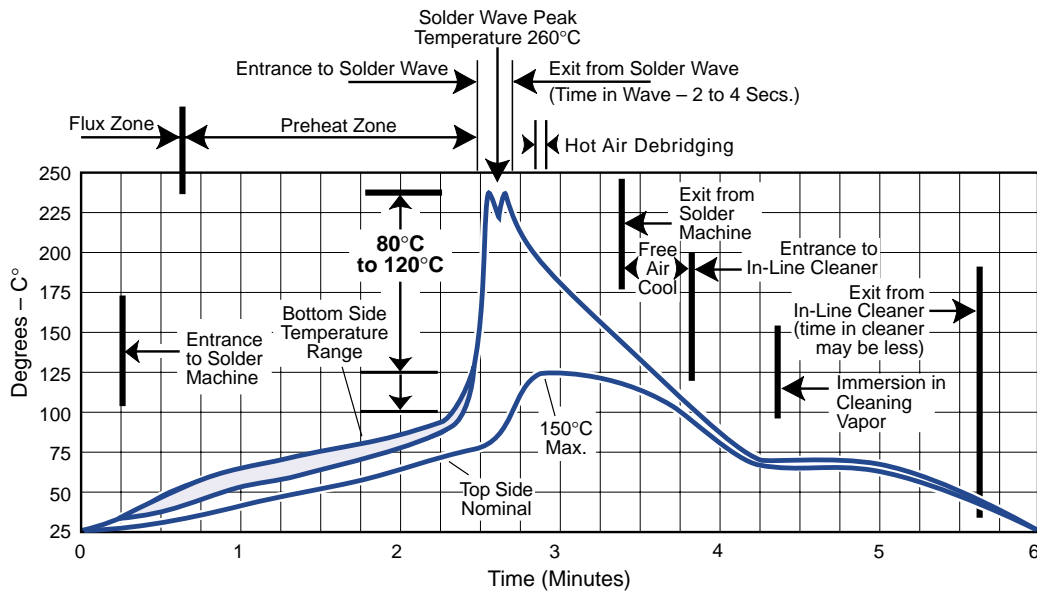


Figure 13.